Search Notes

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Applicant(s)/Patent Under Reexamination

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08/03/2006

LL

10622294 CHOWN, DAVID

Examiner Art Unit

SEARCHED Class Subclass Date Examiner 372 102 08/03/2006 41-43, 152, 129, 58, 122, 125 08/03/2006. 398 LL 02/08/2007 12, 24, 93, 49 08/03/2006, 385 LL 02/08/2007

Liu, Li

SEARCH NOTES				
Search Notes	Date	Examiner		
EAST				
USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	08/03/2006, 02/08/2007, 11/27/2007, 5/31-6/13, 2008; 12/29-12/30, 2008	LL		
Google	08/03/2006	LL		
IEEE	08/03/2006, 12/30/2008	LL		

	INTERFERENCE SEA	RCH	
Class	Subclass	Date	Examiner

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